

## SYSTEM AND METHOD FOR TEST SOCKET CALIBRATION

### ABSTRACT OF THE DISCLOSURE

A system and method for calibration of a test socket using a composite waveform. A group of input signal pins of test system are coupled together. A pin belonging to the group is selected as a pin under calibration. A first calibration edge is applied to the pin under calibration. After a delay, a group of complementary edges is applied to the remaining pins of the group. As a result of the coupling of the pins, a response comprising a reflected edge and a transmitted combined edge are produced, which overlap to form a composite waveform. A comparator is used to detect an observable feature in the composite waveform to obtain timing information with respect to the pin under calibration and the remaining pins of the group. Each pin may be analyzed in turn, and the group of pins calibrated using the acquired information.